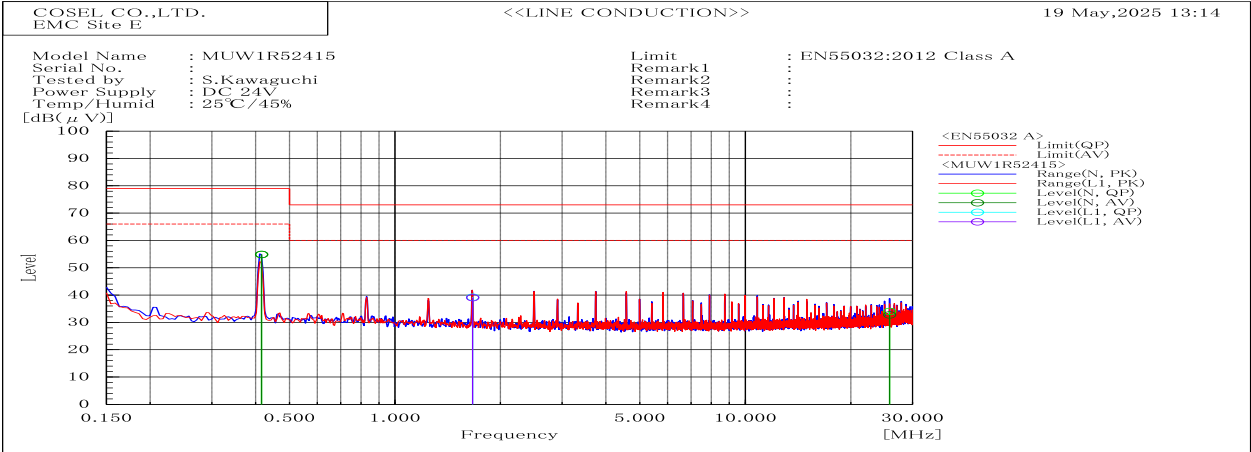
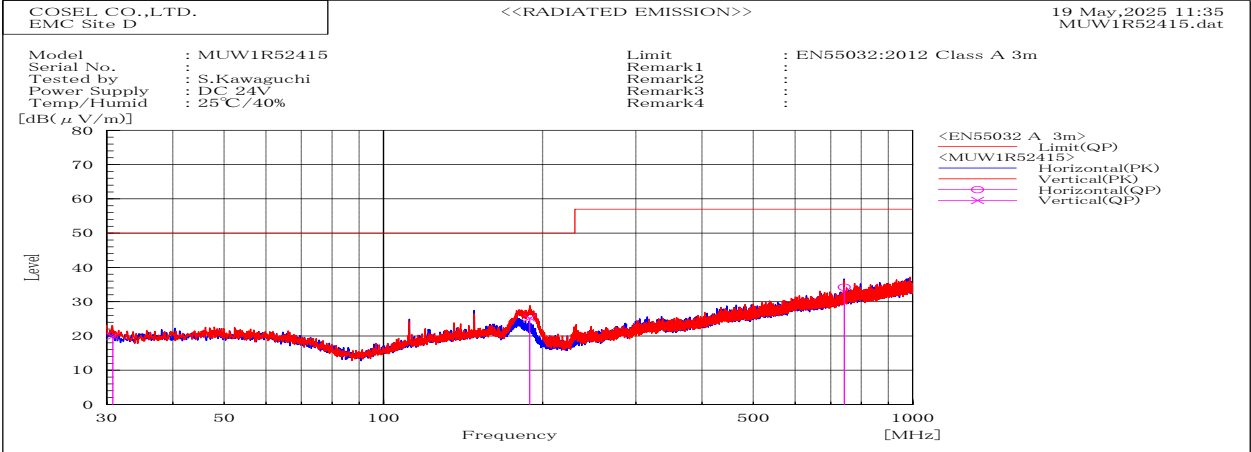


DATA SHEET		Date	19-May-25
Model	MUW1R52415	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi



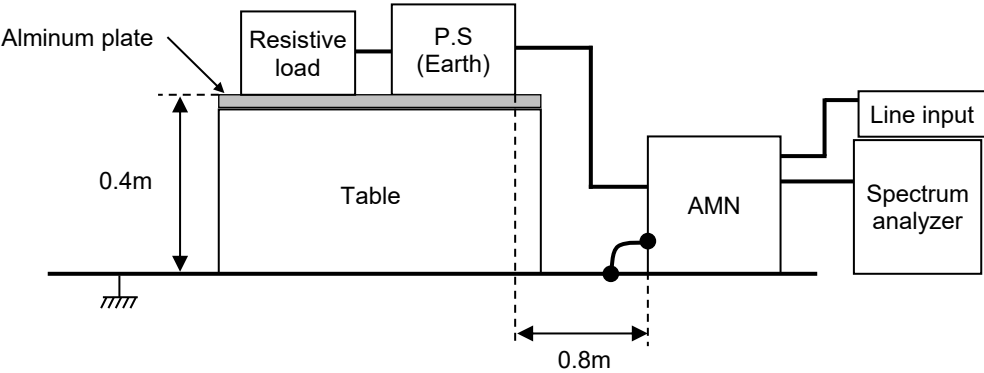
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
0.416	N	54.8	54.9	79	66	24.2	11.1	Pass	
25.809	N	34	32.7	73	60	39	27.3	Pass	
1.665	L1	39.3	39.1	73	60	33.7	20.9	Pass	



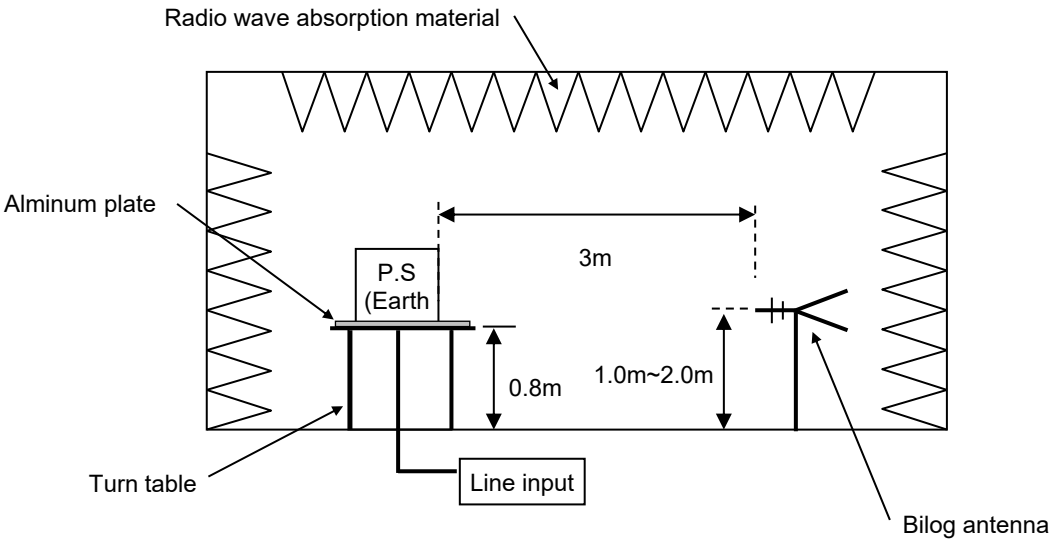
Frequency MHz	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height cm	Angle deg	Remark
			dB(uV/m) QP	dB(uV/m) QP	dB QP				
742.542	H	Stable	34.2	57	22.8	Pass	183	211.4	
30.799	V	Stable	19.9	50	30.1	Pass	100	10.1	
188.909	V	Stable	25.2	50	24.8	Pass	101.7	358.1	

DATA SHEET		Date	19-May-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

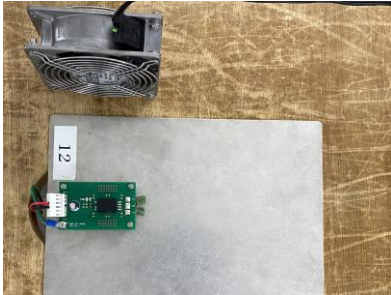
Test : EMI
Model Name: MUW1R5□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

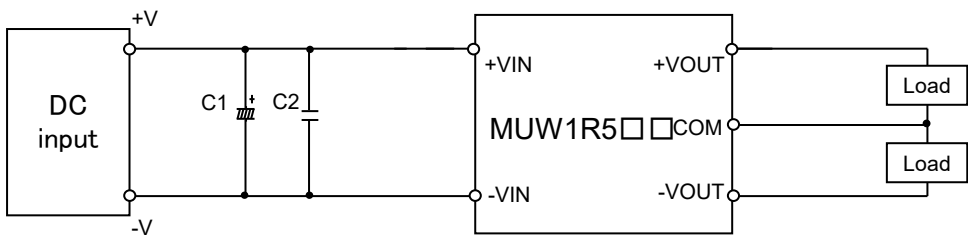


Fig.1 MUW1R505□, MUW1R512□, MUW1R524□ Testing circuitry

- C1 : MUW1R505□ 16V 220 μ F Electric capacitor (UPWseries NICHICON)
MUW1R512□ 50V 100 μ F Electric capacitor (UPWseries NICHICON)
MUW1R524□ -
- C2 : MUW1R505□ 16V 22 μ F Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
MUW1R512□ 25V 22 μ F Ceramic capacitor (C3216JB1E226MT TDK)
MUW1R524□ 50V 10 μ F Ceramic capacitor (C3216X7R1H106KT TDK)

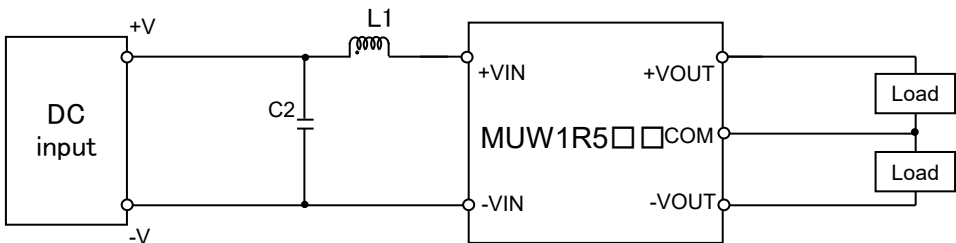


Fig.2 MUW1R548□ Testing circuitry

- C2 : MUW1R548□ 100V 2.2 μ F Ceramic capacitor (C3216X7S2A225KT TDK)
- L1 : MUW1R548□ 520mA 15 μ H Inductor (LQH32PN150MN0L MURATA MANUFACTURING)